A Universal Voltage Level Converter for Multi-V_{DD} Based Low-Power Nano-CMOS Systems-on-Chips (SoCs)

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Mohanty, Vadlamudi and Kougianos 1

Agenda

□ Introduction

- □ Related research works
- Design of ULC
- □ Simulation results at 90nm technology
- □ Characterization of ULC
- Custom layout design at 90nm technology
- Conclusion and future works



Introduction

- Power dissipation reduction has become a major design issue for VLSI design at nano-scale technologies.
- □ Sources of power dissipation
 - Dynamic power
 - Static power
 - Power dissipation due to leakage currents

$$P_{total} = s * C * V_{DD}^{2} * f + I_{sc} * V_{DD} + I_{leakage} * V_{DD}$$



Techniques for power dissipation reduction

Reducing the supply voltage
Transistor sizing
Multiple threshold voltages
Multi-voltage supply systems

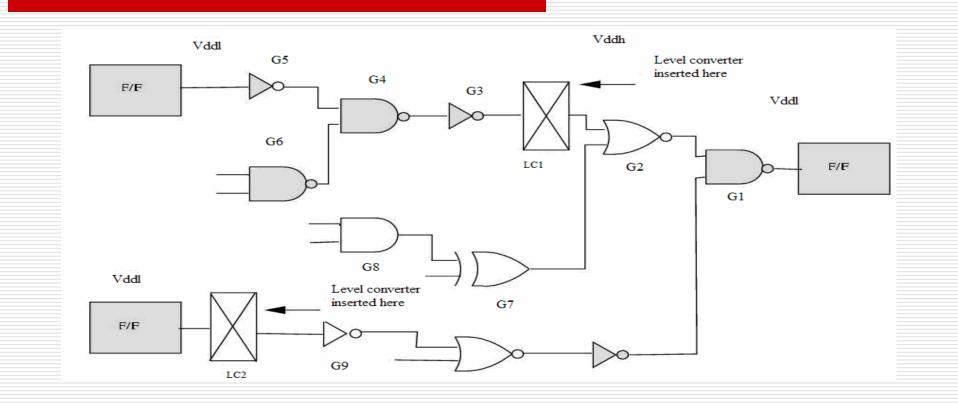


Multi- V_{DD} supply system

- Multiple voltage supply systems are one of the most efficient methods to reduce power dissipation
- The system is divided into voltage islands operating at different supply voltages
- Level converters are used as interface between to voltage islands
- Level converter: A circuit which changes the voltage level at its input to another level at the output side is known as a level converter



Need for level converter

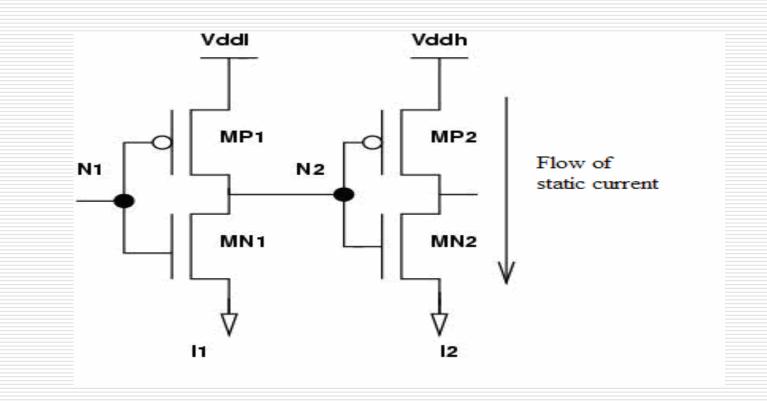


Block diagram of a multi-voltage supply system demonstrating the need for level converter

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Need for a level converter



Direct connection between two inverters demonstrating the need for level converter



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Related research works

- Clustered voltage scaling : Allows insertion of level converters at the interface of cells at different voltages
- Extended clustered voltage scaling : Allows insertion of level converters between any gates, wherever level conversion is required



Related research work (*contd.*.)

Year	Technol ogy	Type of circuit	Design approach	Power consum ption	Delay
2004	0.13mm	Level up converter	Level converting flip flops LCFF		287 ps
1999	0.13mm	Level up converter	DCVS and Keeper transistor		
2001	0.35mm	Level up Converter	Symmetrical Dual Cascode Voltage Switch	220.57 mW	
2006	0.1mm	Level up Converter	Keeper transistor in pass transistor logic		
2000	0.14mm	Level down converter	Differential input pair operation		
2003	0.1mm	Level up converter	Dynamic Level Converter		< 120ps
	2004 1999 2001 2006 2000	ogy 2004 0.13mm 1999 0.13mm 2001 0.35mm 2006 0.1mm 2000 0.14mm	ogycircuit20040.13mmLevel up converter19990.13mmLevel up converter20010.35mmLevel up Converter20060.1mmLevel up Converter20000.14mmLevel down converter20030.1mmLevel up Converter	ogycircuit20040.13mmLevel up converterLevel converting flip flops LCFF19990.13mmLevel up converterDCVS and Keeper transistor20010.35mmLevel up ConverterSymmetrical Dual Cascode Voltage Switch20060.1mmLevel up ConverterKeeper transistor in pass transistor logic20000.14mmLevel down ConverterDifferential input pair operation20030.1mmLevel up ConverterDifferential input pair operation	ogycircuitconsum ption20040.13mmLevel up converterLevel converting flip flops LCFF19990.13mmLevel up

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Universal Level Converter

□ Level up conversion

□ Level down conversion

Blocking of signal

Passing signal



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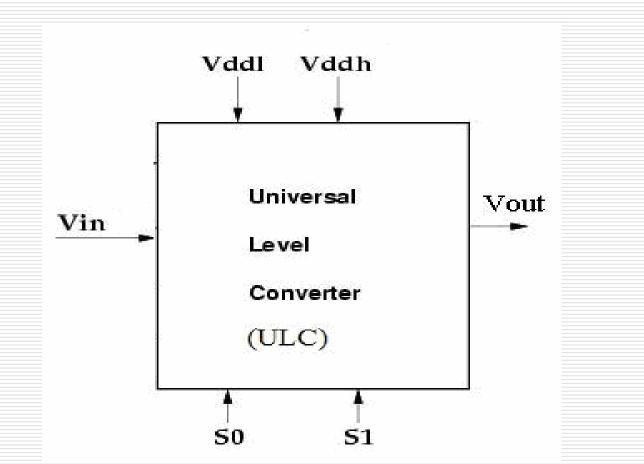
Operations of ULC

Select	signal	Type of
sO	s1	operation
0	0	Passing
		operation
0	1	Blocking
		operation
1	0	Down
		conversion
1	1	Up conversion

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Design of Universal level converter

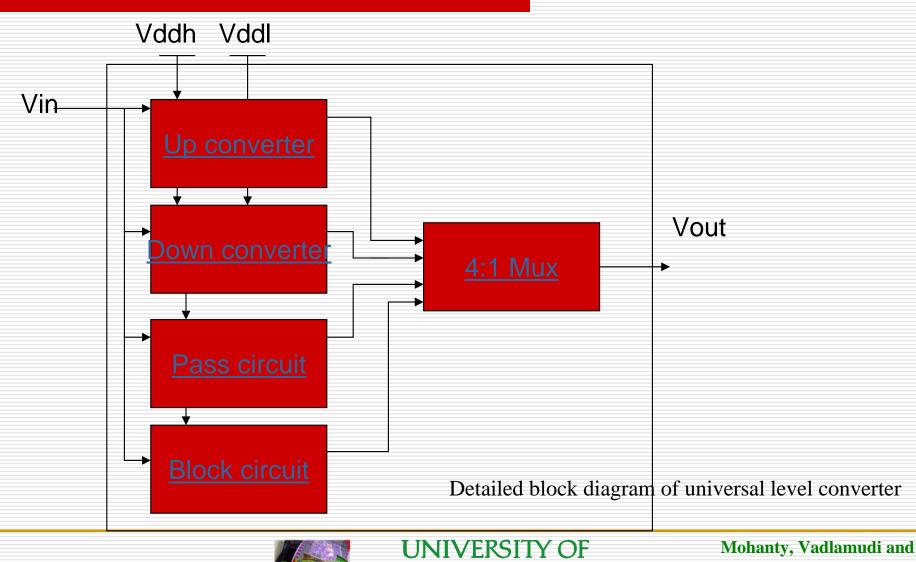


High Level view of Universal level converter proposed

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(Contd..)

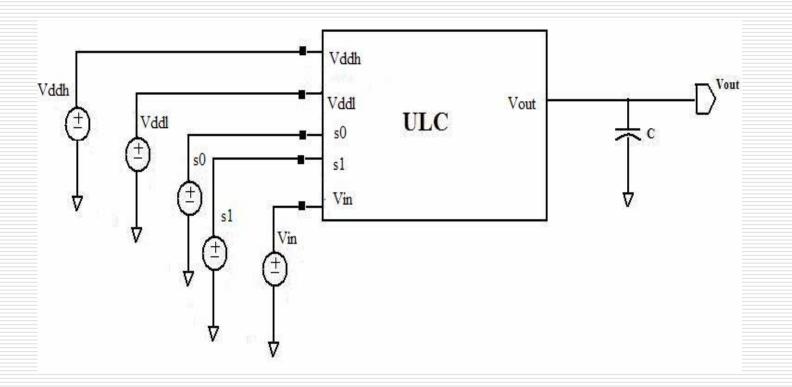


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Simulation test bench



Simulation test bench of universal level converter

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Simulation results of ULC



Simulation results for ULC showing the output waveforms in all modes of operation

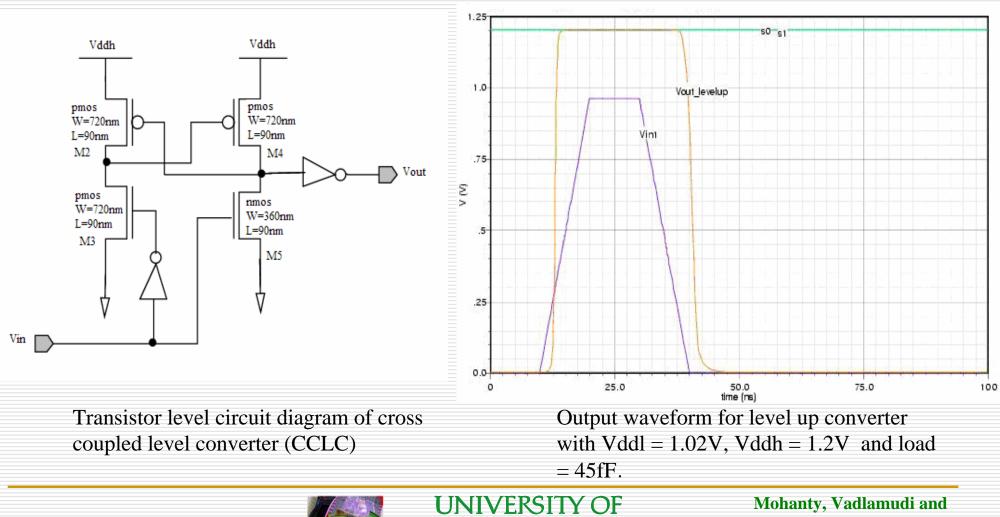
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Level up converter



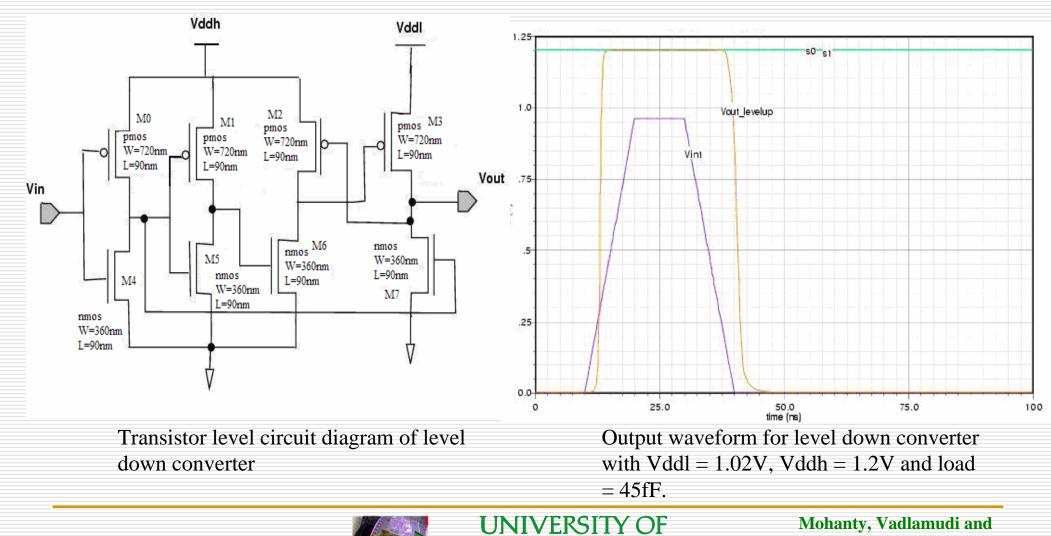
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Level down converter

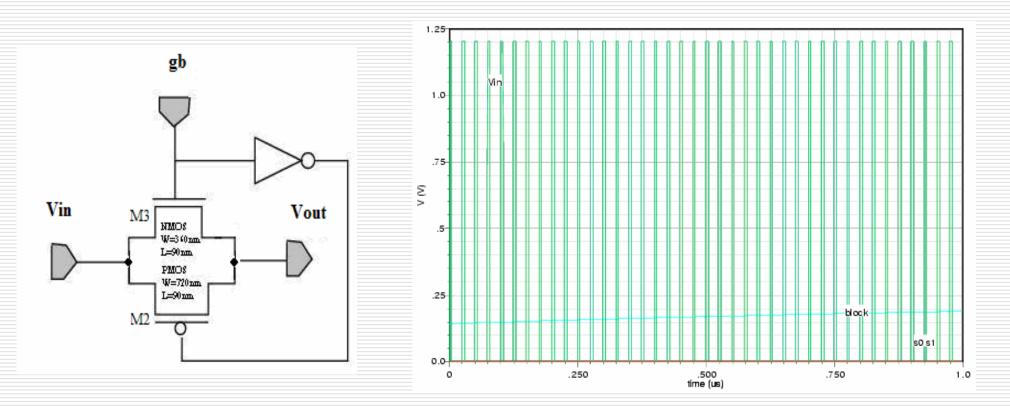


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Level blocking circuit



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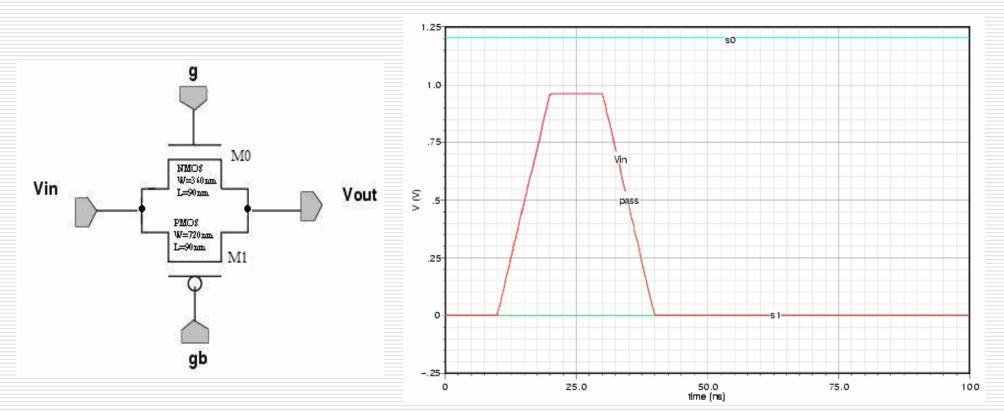
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Transistor level circuit diagram of blocking circuit

Output waveform for level up converter with Vddl = 1.02V, Vddh = 1.2V and load = 45fF.

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Pass circuit



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Transistor level circuit diagram of pass circuit

Output waveform for pass circuit with Vddl = 1.02V, Vddh = 1.2V and load = 45fF.

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Characterization of ULC



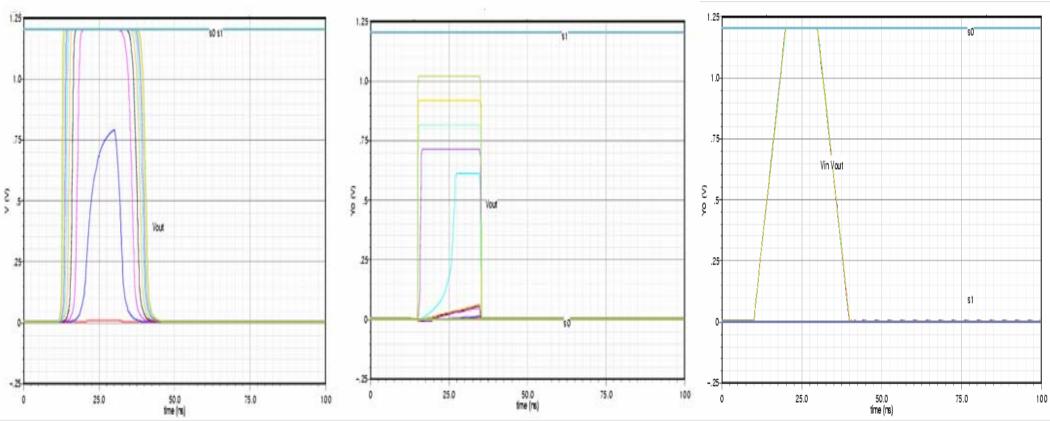
Power analysis

Load analysis



Mohanty, Vadlamudi and Kougianos 20

Parametric analysis



Output waveforms of parametric analysis of ULC where Vddl is varied from 0.1V to 1.02V and Vddh is kept constant at 1.2V

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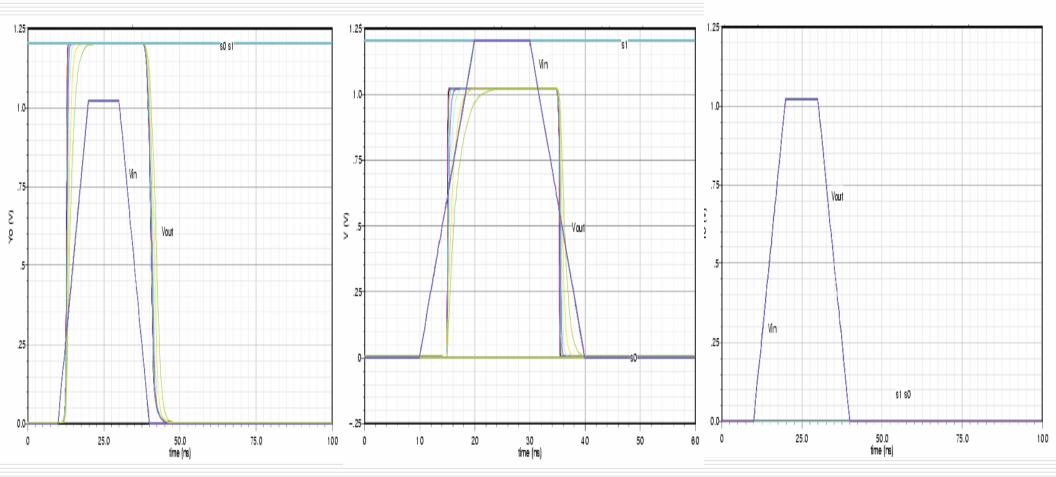
Power analysis

\Box Total average power of ULC = 26.928 μ W



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Load analysis



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Output waveforms of load analysis of ULC where load is varied from 1fF to 200fF.

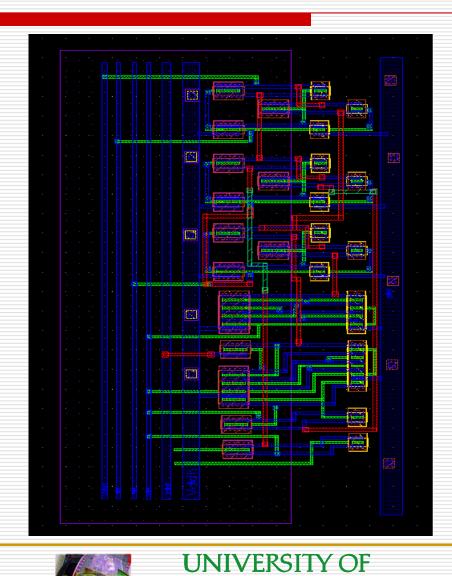
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Custom layout design of ULC

- Layout design of ULC is created at 90nm technology
- \square PMOS W=1µm and L= 100nm
- \square NMOS W= 500nm and L= 100nm
- □ 90nm general process design kit
- Verified using the assuraDRC.rul during DRC check



Universal level converter



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Conclusion

- Proposed a unique level converter design capable of four level converting operations
- Characterized the proposed design using parametric, power and load analysis at 90nm technology
- ULC consumes has an average power reduction of about 85-97% and is capable of producing stable output even under varying load from 1fF -200fF and at voltages as low as 0.6V



Future works

- Proposed design can be improved at schematic as well as layout level. Post layout simulation results to be presented.
- The technology can be further scaled down to 45nm.
- □ ULC design could be improved in the delay aspect.

